

<b>Search Notes</b>  <b>*0999241</b>  <b>3*</b>	<b>Application/Control No.</b>  09992413	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG ET AL.
	<b>Examiner</b>  Benoit, Esther	<b>Art Unit</b>  2453

SEARCHED			
Class	Subclass	Date	Examiner
709	203-230, 245-48	6/13/07	AMN
715	500, 516-517,969	6/13/07	AMN
710	8, 10	6/13/07	AMN
358	1.1	3/29/09	AMN
	Update Search	12/9/2010	EB

SEARCH NOTES		
Search Notes	Date	Examiner
East Search (USPAT; USPGPUB; EPO: JPO: DERWENT; IBM_TDB)	6/13/07	AMN
Inventor Name Search for ODP	6/16/07	AMN
updated East search	3/29/09	AMN
updated inventor name search	3/29/09	AMN
updated East search	1/18/09	AMN
updated classification and inventor name search	5/18/10	AMN
Update Search	12/9/2010	EB
Assignee Search	12/13/2010	EB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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